



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: I-0809-01	DATE September 22, 2008	MEANS OF DISTINGUISHING CHANGED DEVICES:
Product Affected: 89HPES24T6G2, 89HPES24T3G2., 89HPES16T4AG2, 89HPES6T6G2, 89HPES4T4G2		<input checked="" type="checkbox"/> Product Mark Change in Ordering Part Number
Date Effective: 09/22/2008		<input type="checkbox"/> Back Mark
		<input type="checkbox"/> Date Code
		<input type="checkbox"/> Other

Contact: PS Tow	Attachment:: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No
Title: Quality Assurance Director	
Phone #: (408) 284-8206	Samples: N/A
Fax #: (408) 284-8362	
E-mail: PS.Tow@idt.com	

DESCRIPTION AND PURPOSE OF CHANGE:

<input type="checkbox"/> Die Technology	This notification is to advise our customers that IDT has qualified a new die revision to address device errata. The details are as follow:
<input type="checkbox"/> Wafer Fabrication Process	Device die revision from Mark Revision "ZB" to Mark Revision "ZC" for the products affected (listed above).
<input type="checkbox"/> Assembly Process	
<input type="checkbox"/> Equipment	
<input type="checkbox"/> Material	
<input type="checkbox"/> Testing	There will be a change in ordering part number. Please see attachment for details.
<input type="checkbox"/> Manufacturing Site	
<input checked="" type="checkbox"/> Data Sheet	
<input checked="" type="checkbox"/> Other	

RELIABILITY/QUALIFICATION SUMMARY See attached data. There is no change to the die technology/process.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT - PCN #: I- 0809-01

PCN Type: Die revision

Data Sheet Change Yes

Detail of Change This notification is to advise our customers that IDT has qualified a new die revision to address the device errata. The details are as follow:
Device die revision from Mark Revision "ZB" to Mark Revision "ZC" for devices 89HPES24T6G2, 89HPES24T3G2., 89HPES16T4AG2, 89HPES6T6G2, 89HPES4T4G2

There will be a change in ordering part number. Please see Table 1 for details.

The new die revision will address the known errata items as follow:

For Mark Revision "ZB" Errata

1. Eliminate "Less than 16 TS2 sent in response to one received TS2".
2. Eliminate "With both Rx and Tx L0s enabled, link may enter Recovery in some situations".

Table 1

ZB to ZC Transition Parts	
Old Part #	New Part #
89HPES24T6G2ZBAL	89HPES24T6G2ZCAL
89HPES24T6G2ZBALG	89HPES24T6G2ZCALG
89HPES24T3G2ZBAL	89HPES24T3G2ZCAL
89HPES24T3G2ZBALG	89HPES24T3G2ZCALG
89HPES24T3G2ZBBL	89HPES24T3G2ZCBL
89HPES24T3G2ZBBLG	89HPES24T3G2ZCBLG
89HPES24T3G2ZBBR	89HPES24T3G2ZCBR
89HPES16T4AG2ZBAL	89HPES16T4AG2ZCAL
89HPES16T4AG2ZBALG	89HPES16T4AG2ZCALG
89HPES6T6G2ZBAL	89HPES6T6G2ZCAL
89HPES6T6G2ZBALG	89HPES6T6G2ZCALG
89HPES4T4G2ZBAL	89HPES4T4G2ZCAL
89HPES4T4G2ZBALG	89HPES4T4G2ZCALG

Note: For T&R, "8" suffix is added to the part#



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Qualification Data

Test Vehicle: 89HPES24T6G2

Qualification Test Plan and Results:

Test Description	Sample Size/ # Of Fails	Test Results (SS/ # Of Fails)
Dynamic High Temp Operating Life Test	77/0	77/0
* Temperature Cycling (-65 °C to 150 °C, 500 cycle)	45/0	45/0
* Highly Accelerated Stress Test (HAST) (130 °C,85% RH, 100 Hrs)	45/0	45/0
ESD HBM	3/0	3/0
ESD CDM	3/0	3/0

Notes: * Test requires Moisture Pre-Conditioning sequence.